L Number	Hits	Search Text	DB	Time stamp
1	49	("6287703" "5742176" "5597486" "5369495" "5025145" "5177351" "5462879" "5518694" "5623095" "4420567" "4846955" "6108607" "4336111" "4609991" "4774956" "4834842" "4908202" "5194910" "5218856" "5292664" "5319421" "5907401" "5931779" "6103545" "6212938" "6212938" "5636135" "4295045" "4369647" "5420617" "6162281" "6395508" "4409480" "5441613" "4299657" "4627955" "5233992" "5624539" "5980708" "5991352" "6172759" "6328700" "6337018" "6362009" "4956144" "4990308" "5000913" "5026522" "5350936" "5405793").pn.	USPAT; US-PGPUB	2004/03/26 15:09

10681611_CLS
Most Frequently Occurring Classifications of Patents Returned From A Search of 10681611 on March 26, 2004

Original Classifications

3	420/426
2	73/23.36

Cross-Reference Classifications

3	420/425
2	73/23.2
2	73/23.34
2	73/24.06
2	204/434
2	257/E21.53
2	257/E29.315
2	345/440
2	702/176

Combined Classifications

4	420/426
3	420/425
2	73/23.2
2	73/23.34
2	73/23.36
2	73/24.06
2	204/406
2	204/434
2	205/794
2	257/E21.53
2	257/E29.315
2	345/440
2	376/217
2	702/176

10681611_CLSTITLES

Titles of Most Frequently Occurring Classifications of Patents Returned

From A Search of 10681611 on March 26, 2004

4 420/426 (3 OR, 1 XR)
Class 420 : ALLOYS OR METALLIC COMPOSITIONS
420/425 NIOBIUM BASE
420/426 .Titanium, zirconium, or hafnium containing

3 420/425 (0 OR, 3 XR)
Class 420 : ALLOYS OR METALLIC COMPOSITIONS
420/425 NIOBIUM BASE

2 73/23.2 (0 OR, 2 XR)
Class 073 : MEASURING AND TESTING
73/23.2 GAS ANALYSIS

2 73/23.34 (0 OR, 2 XR)
Class 073 : MEASURING AND TESTING
73/23.2 GAS ANALYSIS
73/23.34 .Odor

2 73/23.36 (2 OR, 0 XR)
Class 073 : MEASURING AND TESTING
73/23.2 GAS ANALYSIS
73/23.35 .Gas chromatography
73/23.36 ..With electrical computer or data processor control

2 73/24.06 (0 OR, 2 XR)
Class 073 : MEASURING AND TESTING
73/23.2 GAS ANALYSIS
73/24.01 .By vibration
73/24.06 ..Detector detail

2 204/406 (1 OR, 1 XR)
Class 204 : CHEMISTRY: ELECTRICAL AND WAVE ENERGY
204/193 APPARATUS
204/194 .Electrolytic
204/400 ..Analysis and testing
204/406 ...With significant electrical circuitry or nominal computer device

2 204/434 (0 OR, 2 XR)
Class 204 : CHEMISTRY: ELECTRICAL AND WAVE ENERGY
204/193 APPARATUS
204/194 .Electrolytic

204/400 ..Analysis and testing
204/434 ...Involving plating, coating or stripping

2 205/794 (1 OR, 1 XR)
Class 205 : ELECTROLYSIS: PROCESSES, COMPOSITIONS USED THEREIN, AND METHODS OF PREPARING THE COMPOSITIONS
205/775 ELECTROLYTIC ANALYSIS OR TESTING (PROCESS AND ELECTROLYTE COMPOSITION)
205/793.5 .Tracking chemical reactions
205/794 ..Coating (e.g., electroless, etc.)

2 257/E21.53 (0 OR, 2 XR)
Class 257 : ACTIVE SOLID-STATE DEVICES
257/E21.515 .....Involving use of mechanical auxiliary part without use of alloying or soldering process, e.g., pressure contacts (EPO)
257/E21.521 .Testing or measuring during manufacture or treatment or reliability measurement, i.e., testing of parts followed by no processing which modifies parts as such (EPO)
257/E21.529 ..Measuring as part of manufacturing process (EPO)
257/E21.53 ...For structural parameters, e.g., thickness, line width, refractive index, temperature, warp, bond strength, defects, optical inspection, electrical measurement of structural dimensions, metallurgic measurement of diffusions (EPO)

2 257/E29.315 (0 OR, 2 XR)
Class 257 : ACTIVE SOLID-STATE DEVICES
257/E29.162 ....Insulating materials for IGFET (EPO)
257/E29.166 .Types of semiconductor device (EPO)
257/E29.169 ..Controllable by only signal applied to control electrode (e.g., base of bipolar transistor, gate of field-effect transistor) (EPO)
257/E29.226 ...Unipolar device (EPO)
257/E29.242 ....Field-effect transistor (EPO)
257/E29.31 .....With field effect produced by PN or other rectifying junction gate (i.e., potential

barrier) (EPO)
257/E29.315 ......With heterojunction gate (e.g., transistors with semiconductor layer acting as gate insulating layer) (EPO)

2 345/440 (0 OR, 2 XR)
Class 345 : COMPUTER GRAPHICS PROCESSING, OPERATOR INTERFACE PROCESSING, AND SELECTIVE VISUAL DISPLAY SYSTEMS
345/418 COMPUTER GRAPHICS PROCESSING
345/440 .Graph generating

2 376/217 (1 OR, 1 XR)
Class 376 : INDUCED NUCLEAR REACTIONS: PROCESSES, SYSTEMS, AND ELEMENTS
376/207 WITH CONTROL OF REACTOR (E.G., CONTROL OF COOLANT FLOW)
376/215 .By electronic signal processing circuitry (e.g., plural redundant circuits)
376/216 ..Plural sensed different conditions or measured variables correlated
376/217 ...Control programs

2 702/176 (0 OR, 2 XR)
Class 702 : DATA PROCESSING: MEASURING, CALIBRATING, OR TESTING
702/127 MEASUREMENT SYSTEM
702/176 .Time duration or rate

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PLUS Search Results for S/N 10681611, Searched March 26, 2004

The Patent Linguistics Utility System (PLUS) is a USPTO automated search system for U.S. Patents from 1971 to the present. PLUS is a query-by-example search system which produces a list of patents that are most closely related linguistically to the application searched. This search was prepared by the staff of the Scientific and Technical Information Center, SIRA.

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